

Notice of References Cited	Application/Control No. 10/079,800	Applicant(s)/Patent Under Reexamination AKUNE ET AL.	
	Examiner Chat C. Do	Art Unit 2124	Page 1 of 1

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	C	US-5,903,857	05-1999	Behrens et al.	708/300
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NON-PATENT DOCUMENTS

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	U	Adrian et al., A two-path bandpass delta-sum modulator for digital IF extraction at 20 MHz, December 1997, IEEE Journal of solid-state circuits, Vol. 32, No. 12, pages 1920-1934.
	V	Krzysztof et al., Effects of noise dither signals on differential linearity and effective resolution of sigma-delta A/C converters in measuring applications, May 1998, IEEE Instrumentation and Measurement Technology Conference, pages 1229-1232.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.